

Figure 1: Continuous etch rate of MoS<sub>2</sub> for different ratios of SF<sub>6</sub> and H<sub>2</sub> in the plasma. Below a ratio of 0.3 there is no continuous etching. In the ALE process a ratio of 0.26 was used.

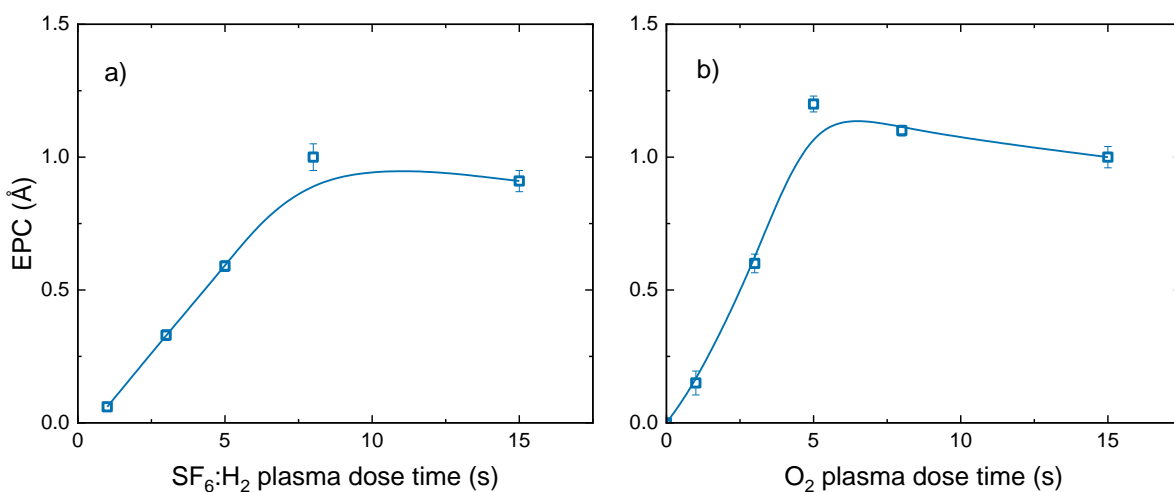


Figure 2: Saturation curves for a) SF<sub>6</sub>/H<sub>2</sub>/Ar plasma step (O<sub>2</sub> plasma time is kept at 10 s) and b) O<sub>2</sub> plasma step (SF<sub>6</sub>/H<sub>2</sub>/Ar plasma time is kept at 10 s). Lines serve as a guide to the eye.

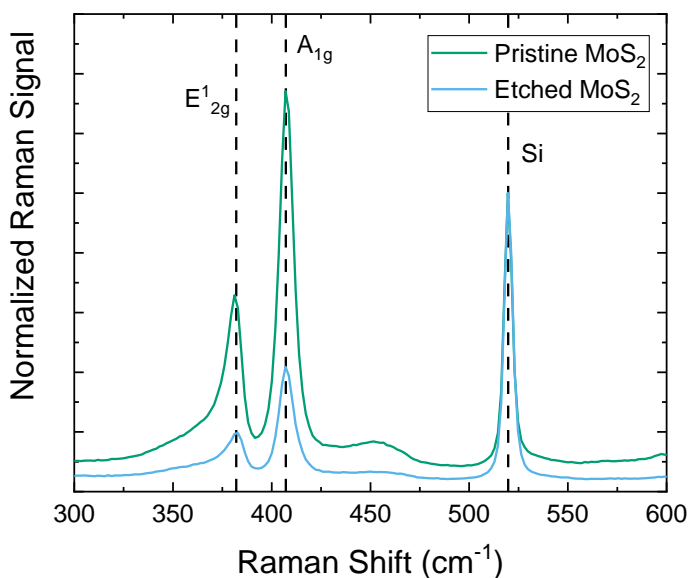


Figure 3: Raman spectra of pristine MoS<sub>2</sub> and MoS<sub>2</sub> etched with 20 cycles of ALE using 8 s SF<sub>6</sub>-based plasma and 10 s O<sub>2</sub> plasma exposures. Spectra are normalized to the Si peak.